Device Failure Analysis

### ML in device failure prediction

Machine Learning (ML) allows for predictions from vast amount of data -> <u>increased reliability</u>

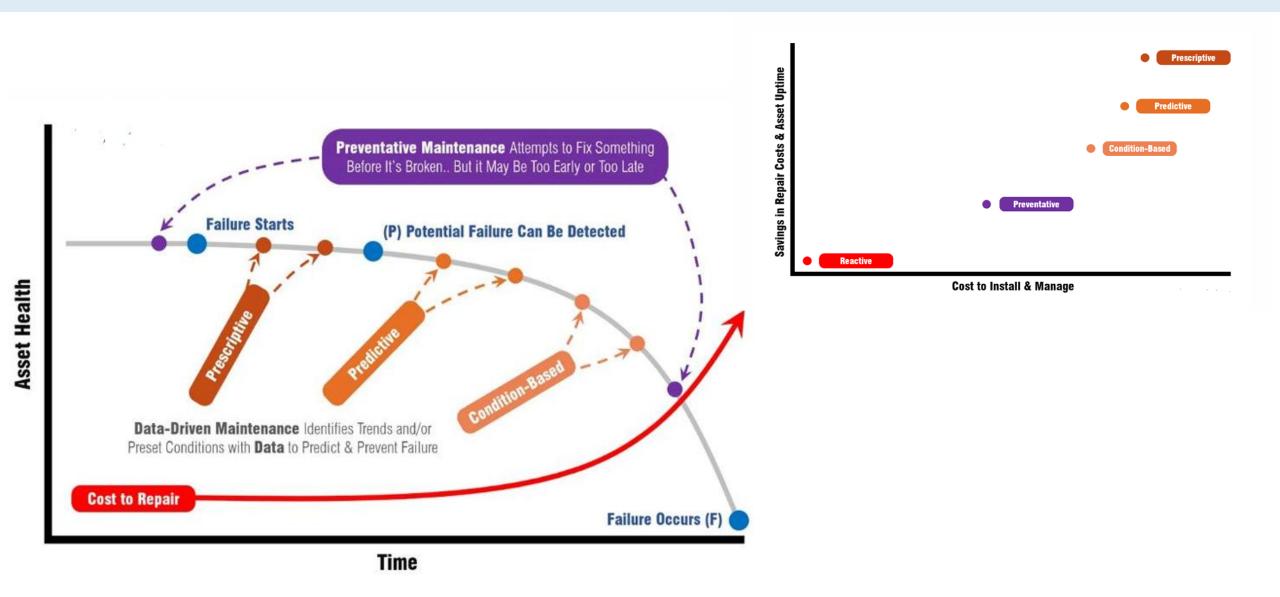
 ML allows engineers to take proactive steps by providing early warning signs of impending failures/malfunctions -> <u>proactive maintenance</u>

ML allows savings in time and money by reducing downtime and increasing productivity -> <u>improved</u>

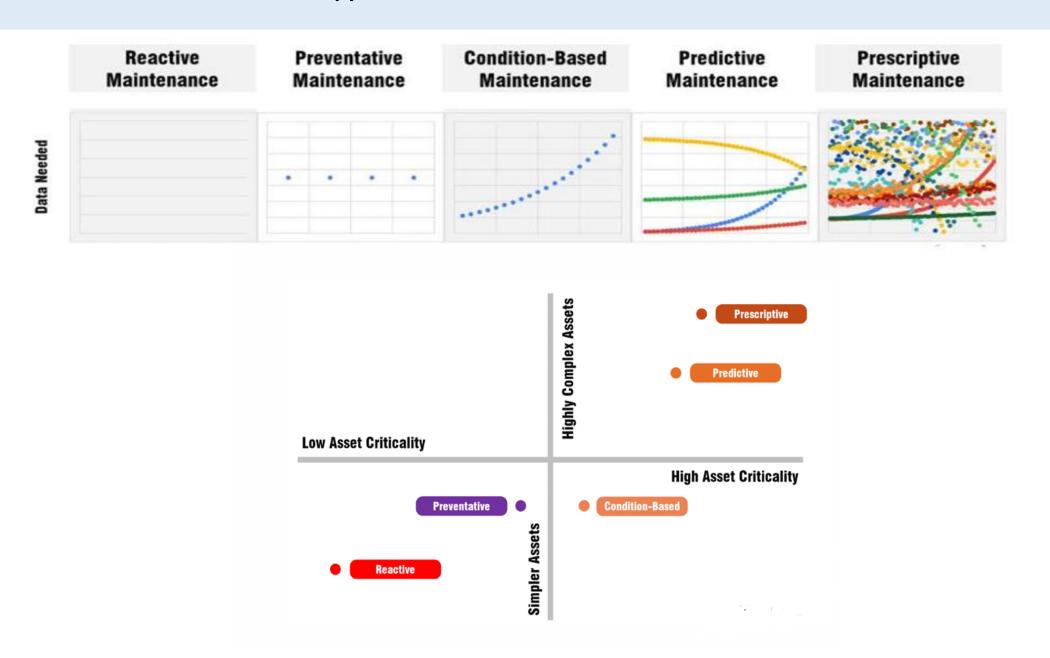
<u>efficiency</u>



#### Predictive maintenance offers cost savings compared to preventive maintenance



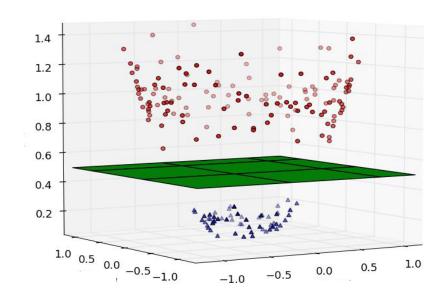
#### Which asset type needs what kind of maintenance?

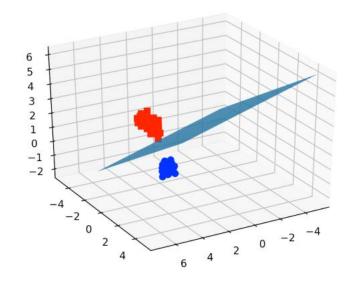


### Methodology

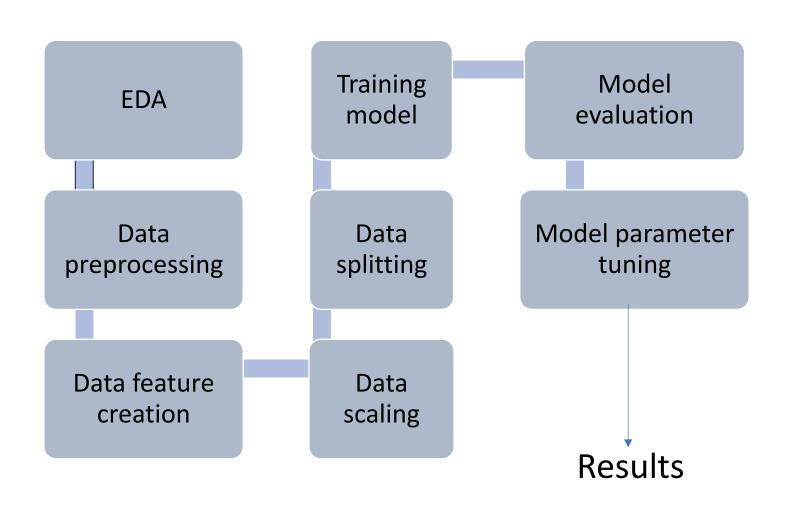
- Supervised learning: classification
- Model training data is labelled and the data provided is of 1 year (2015)
- Response class in data is binary, target or response is termed 'malfunction': 0 is non-failure and 1 is failure
- Logistic Regression is explored to predict malfunction/failure using data of a fleet of devices/products

#	Column	Non-Null Count	Dtype
0	date	124494 non-null	object
1	product	124494 non-null	object
2	malfunction	124494 non-null	int64
3	feature1	124494 non-null	int64
4	feature2	124494 non-null	int64
5	feature3	124494 non-null	int64
6	feature4	124494 non-null	int64
7	feature5	124494 non-null	int64
8	feature6	124494 non-null	int64
9	feature7	124494 non-null	int64
10	feature8	124494 non-null	int64
11	feature9	124494 non-null	int64





# Approach



## Challenges

- Data understanding, especially when there is imbalance
- Dataset is a mix of qualitative and quantitative data
- Minimizing FPs and FNs, while retaining good performance of the model
- Choosing the right metric for model assessment
- Choosing the right metric to validate the model for business value-addition



#### Discussion

 Very high model accuracy score may mean either too few observations or training examples or too high regularization of features

 Feature Engineering is essential when we have data with large number of features with proper understanding of each from a domain or SM expert, and how they can impact device failure.

solver	penalty	multinomial multiclass
'lbfgs'	'12', None	yes
'liblinear'	'11', '12'	no
'newton-cg'	'l2', None	yes
'newton-cholesky'	'12', None	no
'sag'	'12', None	yes
'saga'	'elasticnet', 'l1', 'l2', None	yes